

Notice of References Cited

Application/Control No.

10/560,453

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

3768

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English translation of JP Patent 2003-029138 provided by the IPDL tool
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